

Enhancement Mode N-Channel Power MOSFET

 $TO-220/NMOS/40V/\pm20V/1.6V/230A/1.8m\Omega$

Rev0.1





40V, 1.8mΩ, 230A, N-Channel MOSFET

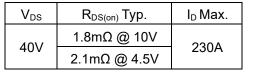
1.Features

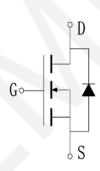
- Advanced Trench Technology
- ◆ Excellent R_{DS(ON)} and Low Gate Charge
- ◆ Lead Free
- ◆ 100% RG Tested
- ◆ 100% UIS Tested

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Z.A	μμ	1116	นแบ	112

- ◆ Load Switch
- ◆ PWM Application
- ◆ Power Management







Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Tube	PCS/CTN.
WX018N04KA	018N04	TO-220	50	5,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	$V_{ extsf{DSS}}$	40	V
Gate to Source Voltage	V _{GSS}	±20	V
Drain Current (DC)	I _D	230	А
Drain Current (Pulse), PW≤300μs	I _{DP}	920	А
Total Dissipation	P _D	156	W
Avalanche Energy, Single Pulsed	E _{AS}	486	mJ
Junction Temperature	T _j	150	°C
Storage Temperature	T _{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Junction to Ambient	$R_{ hetaJA}$	41	°C/W
Junction to case	$R_{ heta JC}$	0.8	°C/W

Note 2: When mounted on 1 inch square copper board t ≤ 10sec The value in any given application depends on the user's specific board design.

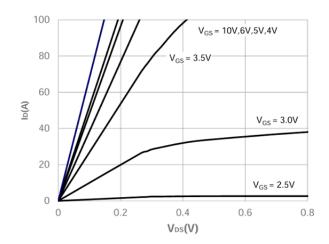
6.Electrical Characteristics at Ta=25°C (Note 3)

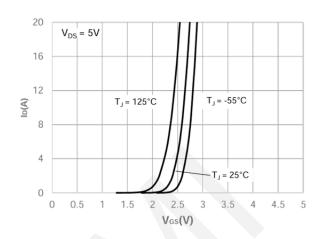
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A, V_{GS} = 0 V$	40	1	1	V
Zero-Gate Voltage Drain Current	I _{DSS}	V_{DS} =40V, V_{GS} = 0V	ı	-	1	μΑ
Gate to Source Leakage Current	I _{GSS1}	$V_{GS} = \pm 20V$, $V_{DS} = 0V$	ı	-	±100	nA
Gate Threshold Voltage	$V_{\text{GS(th)}}$	V_{DS} = V_{GS} , I_{DS} =250 μ A	1.0	1.6	2.5	V
Static Drain to Source On-State	Б	I _D =30A, V _{GS} = 10V	-	1.8	2.5	mΩ
Resistance	R _{DS(on)}	$I_D = 20A, V_{GS} = 4.5V$		2.1	2.7	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V,	•	12138	ı	pF
Output Capacitance	C _{oss}	V _{DS} =20V,	-	774	-	pF
Reverse Transfer Capacitance	C _{rss}	Frequency=1.0MHz	-	651	-	pF
Turn-on Delay Time	t _{d(on)}		-	17	-	ns
Rise Time t _r		$V_{DS} = 20V, V_{GS} = 10V,$	-	17	-	ns
Turn-off Delay Time	$t_{d(off)}$	$I_D = 1A, R_{GEN} = 3\Omega$	-	234	-	ns
Fall Time	t _f		-	73	-	ns
	Q_g	V _{DS} =20V,	-	224	-	nC
Total Gate Charge	Q_{gs}	$V_{GS} = 0$ to 10V,	-	34	-	nC
	Q_{gd}	I _D =1A	-	33	-	nC
Diode Forward Voltage	V_{FSD}	I _S =30A, V _{GS} =0	-	-	1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

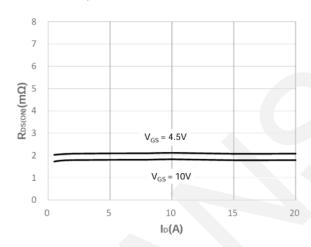


7. Typical electrical and thermal characteristics

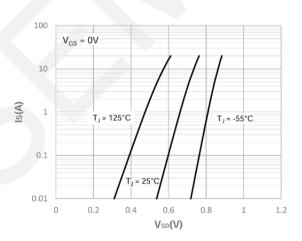




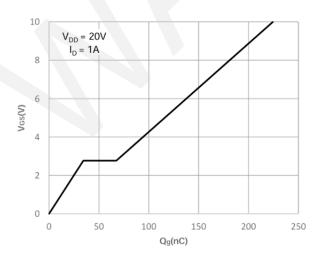
Output Characteristics



Typical Transfer Characteristics

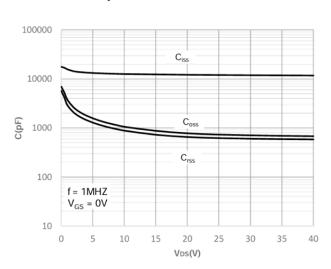


On-resistance vs. Drain Current



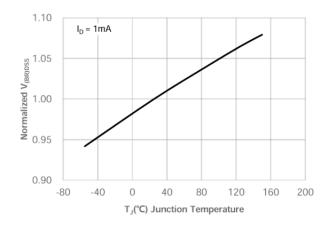
Gate Charge Characteristics

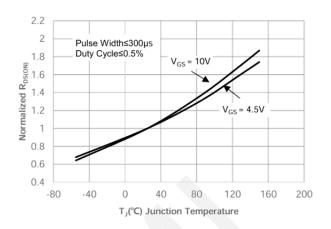
Body Diode Characteristics



Capacitance Characteristics

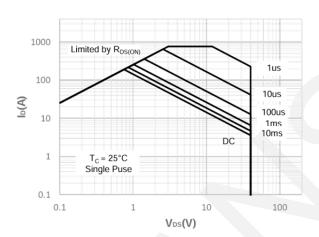






Normalized Breakdown Voltage vs.

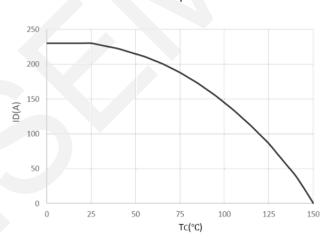
Junction Temperature



Maximum Safe Operating Area

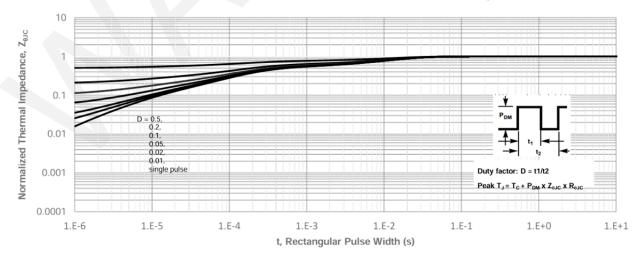
Normalized on Resistance vs.

Junction Temperature



Maximum Continuous Drain Current vs.

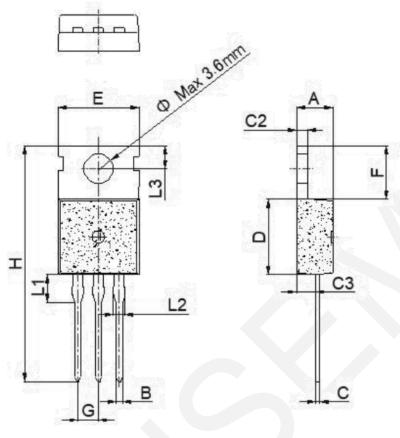
Case Temperature



Normalized Maximum Transient Thermal Impedance



8.Package Dimensions



	Dimensions							
Ref.	Millimeters			Inches				
	Min.	Тур.	Max.	Min.	Тур.	Max.		
Α	4.40		4.60	0.173		0.181		
В	0.70		0.90	0.028		0.035		
С	0.45		0.60	0.018		0.024		
C2	1.23		1.32	0.048		0.052		
C3	2.20		2.60	0.087	70	0.102		
D	8.90		9.90	0.350		0.390		
E	9.90		10.3	0.390		0.406		
F	6.30		6.90	0.248		0.272		
G		2.54			0.1			
Н	28.0		29.8	1.102		1.173		
L1		3.39	2		0.133	9 176 10		
L2	1.14		1.70	0.045		0.067		
L3	2.65		2.95	0.104		0.116		
Ф		3.6			0.142			



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